

CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Resion, LLC

7060 Havertys Way Lakeland, FL 33805

Fulfills the requirements of

ISO/IEC 17025:2017

and the

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document. The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President
Expiry Date: 20 December 2024
Certificate Number: AT-3160









SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Resion, LLC

7060 Havertys Way
Lakeland, FL 33805
Anne Poncheri aponcheri@resion.com
516 620 0135

TESTING

Valid to: December 20, 2024 Certificate Number: AT-3160

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **Resion**, **LLC** to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

Version 003 Issued: April 19, 2023

Specific Tests and/or Properties Measured	Specificati <mark>on, Standard,</mark> Method, or Test Technique	It <mark>ems, M</mark> aterials or Product Tested	Key Equipment or Technology
Radiographic Examination / Inspection	Internal Procedure: WI 60- 06 IDEA-STD-1010B AS6081 AS6171/5	Electrical, Electronic and Electromechanical (EEE) Components	Glenbrook RTX-113
Visual Inspection	Internal Procedure: WI 60- 04 IDEA-STD-1010B AS6081 AS6171/2 Method A, Method B, excluding weight	Electrical, Electronic and Electromechanical (EEE) Components	Keyence VHX-970F
Elemental Content by XRF	Internal Procedure: WI 60- 08 IDEA-STD-1010B AS6081 AS6171/3	Electrical, Electronic and Electromechanical (EEE) Components	Fischer-XDAL 237 Benchtop XRF





Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation and Die Verification	Internal Procedure: WI 60-07 IDEA-STD-1010B AS6081 AS6171/4 Chemical Decapsulation Bake Method Mechanical Disassembly	Electrical, Electronic and Electromechanical (EEE) Components	Nisene Jet-Etch Decapulator, Oven, Meiji MC50T
Solderability	Internal Procedure: WI 60-14 J-STD-002	Electrical, Electronic and Electromechanical (EEE) Components	Solder Pot Thermocouple
Remarking/Resurfacing	Internal Procedure: WI 60-05 IDEA-STD-1010B AS6081 AS6171/2 Method C and D	Electrical, Electronic and Electromechanical (EEE) Components	Chemical Test
Dimensions	Internal Procedure: WI 60-04 MIL-STD-883 Method 2016 IDEA-STD-1010B AS6081, AS6171/2, Method E	Electrical, Electronic and Electromechanical (EEE) Components	Keyence VHX-970F Digital Calipers
Scrape Test	Internal Procedure: WI 60-05 IDEA-STD-1010B AS6171/2 Method D	Electrical, Electronic and Electromechanical (EEE) Components	Mechanical Removal of Surface

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-3160.

Jason Stine, Vice President

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